



**AgEcon** SEARCH  
RESEARCH IN AGRICULTURAL & APPLIED ECONOMICS

*The World's Largest Open Access Agricultural & Applied Economics Digital Library*

**This document is discoverable and free to researchers across the globe due to the work of AgEcon Search.**

**Help ensure our sustainability.**

Give to AgEcon Search

AgEcon Search  
<http://ageconsearch.umn.edu>  
[aesearch@umn.edu](mailto:aesearch@umn.edu)

*Papers downloaded from **AgEcon Search** may be used for non-commercial purposes and personal study only. No other use, including posting to another Internet site, is permitted without permission from the copyright owner (not AgEcon Search), or as allowed under the provisions of Fair Use, U.S. Copyright Act, Title 17 U.S.C.*

**Permanent and Temporary Shocks in Corn and Soybean Basis Series**  
**: A New Approach for Modeling Time-Series**

**Yoonsuk Lee**

Aquaculture/Fisheries Center  
University of Arkansas at Pine Bluff  
Pine Bluff, 71601  
Phone: 870-575-9809  
Fax: 807-575-4637  
Email: [keynes833@hotmail.com](mailto:keynes833@hotmail.com)

**B. Wade Brorsen**

Department of Agricultural Economics  
Oklahoma State University  
Stillwater, OK 74078  
Phone: 405-744-6836  
Fax: 405-744-8210  
Email: [wade.brorsen@okstate.edu](mailto:wade.brorsen@okstate.edu)

*Selected Paper prepared for presentation at the Agricultural & Applied Economics  
Association's 2013 AAEA Annual Meeting, Washington, DC, August 4-6, 2012*

*Copyright 2013 by Yoonsuk Lee and B. Wade Brorsen. All rights reserved. Readers may make  
verbatim copies of this document for non-commercial purposes by any means, provided that this  
copyright notice appears on all such copies.*



# Permanent and Temporary Shocks in Corn and Soybean Basis Series : A New Approach for Modeling Time-Series

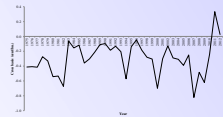
Yoonsuk Lee and B. Wade Brorsen  
Department of Agricultural Economics, Oklahoma State University



## Introduction

- Various time-series models have attempted to explain features of time-series data caused by irregular events.
- Such irregular events are distinguished between permanent and temporary shocks in this study.
- This study develops a new stochastic time-series model that imposes different distributions into permanent and temporary shocks, respectively.
- Corn basis and soybean basis series are selected as primary examples of realistic time-series data

Illinois Corn for Harvest Basis from 1975 to 2012



Illinois Soybean for Harvest Basis from 1975 to 2009



## Objectives

- Propose a single stochastic process to include permanent and temporary shocks:
  - Permanent shocks are reflected by a Bernoulli-jump process
  - Temporary shocks are explained by an independent and identically distributed normal distribution
- Determine whether the proposed model is well calibrated through the indirect inference of comparing with ARIMA models with outliers.

Contact Yoonsuk : keynes833@hotmail.com  
Dr. Brorsen: wade.brorsen@okstate.edu

## Model Development

### Bernoulli-jump Model

The data generating process mixed with a Bernoulli process is expressed as:

$$\begin{aligned} \text{Series}_t &= a_t + e_t \\ a_t &= a_{t-1} + \beta + B_t J_t \\ \Delta \text{series}_t &= \text{series}_t - \text{series}_{t-1} \\ &= \beta + B_t J_t + e_t - e_{t-1} \end{aligned}$$

where  $\text{Series}_t$  is a series at time  $t$ ,  $a_t$  is an observed variable which assumed to explain a permanent shock occurring in a given time  $t$ ,  $e_t$  are the temporary shocks and follows an i.i.d  $N(0, \sigma_e^2)$ ,  $E(e_t e_{t-1}) = 0$ ,  $\beta$  is a drift,  $J_t$  follows i.i.d  $N(\mu_J, \sigma_J^2)$ ,  $B_t$  represents one permanent shock and follows a Bernoulli ( $P$ ) process,  $P$  is the probability of one permanent shock and  $B_t$  and  $J_t$  are independent.

### ARIMA with outliers (Competing model)

Based on the outlier specification of Tsay (1988), the ARIMA with outliers model can be written as:

$$Z_t = w_0 + \frac{\Phi(L)}{\Theta(L)} \epsilon_t^{(D)} + Y_t$$

where  $Z_t$  is a series contaminated by outliers at time  $t$ ,  $\frac{\Phi(L)}{\Theta(L)}$  represents the characteristics of outliers,  $\epsilon_t^{(D)}$  is dummy variable for outliers occurring at time point  $D$ ,  $\epsilon_t^{(D)} = 1$  if  $t=D$  and  $\epsilon_t^{(D)} = 0$  if  $t \neq D$ .

## Procedures

### Bernoulli-jump Model

- Gallant and Tauchen's (1996) approach for the GMM estimation to estimate the proposed model
- Take a first order condition of the assumed log-likelihood function of the proposed model with respect to parameters
- Each f.o.c becomes a moment condition for the GMM estimation
- In order to handle autocorrelation in the series, add an additional moment condition about autocorrelation

Reference  
Gallant, A.R., and G.E. Tauchen. 1996. "Which Moments to Match?" *Econometric Theory* 12:657-681  
Tsay, R.S. 1988. "Outlier, Level Shifts, and Variance Changes in Time Series." *Journal of Forecasting* 7:1-20

## Results

### Bernoulli-jump Model

- Find most shocks are related with permanent shocks in corn and soybean basis series.

Parameter Estimates from the Proposed Model

Parameters	Corn Basis	Soybean Basis
	GMM with Autocorrelation	GMM with Autocorrelation
Drift	-0.0392 (0.0441)	-0.0103 (0.0471)
Jump mean	0.0927 (0.1120)	0.0287 (0.0847)
Variance	0.0057 (0.0041)	0.0032 (0.0052)
Jump variance	0.0854 (0.0147)	0.0742 (0.0258)
Probability of jump	0.5247 (0.0991)	0.6857 (0.2085)

Note: numbers in parenthesis are standard errors.

### ARIMA with outliers

- Find a transient change outliers around 2010 in corn basis and there is no outlier in soybean basis.

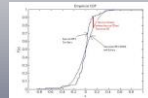
Parameter Estimates from ARIMA with Outliers

Parameters	Estimates	P-value	Years	Types
Corn basis (ARIMA (0,1,1) with LS and TS)				
MA(1)	0.769	<.0001		
Outlier1	0.505	0.0002	2010	Transient Change
Soybean basis (ARIMA (0,1,1) with LS and TS)				
MA(1)	0.810	<.0001		
No outlier				

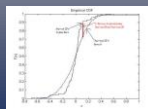
### Calibration Tests

- For the indirect inference of a better fit to data, an empirical distribution function statistics are used.
- The proposed Bernoulli-jump model reflect the feature of corn and soybean basis series, reasonably well.

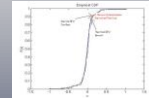
K-S Test of Empirical CDF of Corn Basis under Theoretical CDF of ARIMA model with Outliers



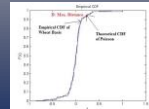
K-S Test of Empirical CDF of Soybean Basis under Theoretical CDF of ARIMA model with Outliers



K-S Test of Empirical CDF of Corn Basis under Theoretical CDF of Bernoulli Model



K-S Test of Empirical CDF of Soybean Basis under Theoretical CDF of Bernoulli Model



printed by **MEGA Print Inc.** www.megaprint.com